

Application/Control No.	Appl
	Reex

Applicant(s)/Patent under Reexamination

10/043,489

Examiner

David E. Martinez

DUGAN ET AL.

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SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
East - See attached	12/19/2005	DM
Inventor Search eDan	12/19/2005	DM
Databases: US Patents, US PGPUBS, USOCR, EPO, Derwen,t IBM_TDB.	12/19/2005	DM
710/5,19,36.ccls. 709/223,225- 229,245,250.ccls.	12/19/2005	DM